

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Keerthinarayan P. HERAGU et al. Group Art Unit:
Serial No : Examiner:
Filed : August 5, 2003 Conf. No.:
For : Self-Timed Strobe Generator and Method for Use with Multi-Strobe
Random Access Memories to Increase Memory Bandwidth

INFORMATION DISCLOSURE STATEMENT

COMMISSIONER FOR PATENTS
P.O. BOX 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. §§1.97 and 1.98, Applicants hereby submit copies of the patents and publications listed in the accompanying Form PTO-1449 for consideration by the Examiner, each of which are believed to be relevant to the above-identified patent application.

Respectfully submitted,

By:



Alan K. Stewart
Registration No. 35,373
Texas Instruments Incorporated
P.O. Box 655474
MS 3999
Dallas, TX 75265
(972) 917-5466

Dated: August 5, 2003

Charles A. Rattner
PTO Reg. No. 40,136

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	Complete if Known	
	Application Number	
	Filing Date	August 5, 2003
	First Named Inventor	Keerthinarayan P. Heragu et al.
	Group Art Unit	
	Examiner Name	
Sheet 1 of 1	Attorney Docket No: TI-35285	

US PATENT DOCUMENTS						
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US 6,580,305	06/17/2003	Liu et al.	327	298	12/29/1999
	US 6,496,445	12/17/2002	Lee	365	233	09/05/2001
	US 6,456,544	09/24/2002	Zumkher	365	193	03/30/2001
	US 5,802,555	09/01/1998	Shigeeda	711	106	03/13/1997

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T ²

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ²

EXAMINER

DATE CONSIDERED